Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/089,107	SANO ET AL.
Examiner	Art Unit
John Pezzlo	2616

SEARCHED					
Class	Subclass	Date	Examiner		
370	330,32 208,481	9			
	430 430				
375	131, 225 130, 146 142, 276- 222 452	1/13	-16/06		
	130,142		· 36		
	142,220				
455	452				
		خستم			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
refer to EAST Search ?				
refer to IEEE Slaveh	2/15/0	s gp		
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